

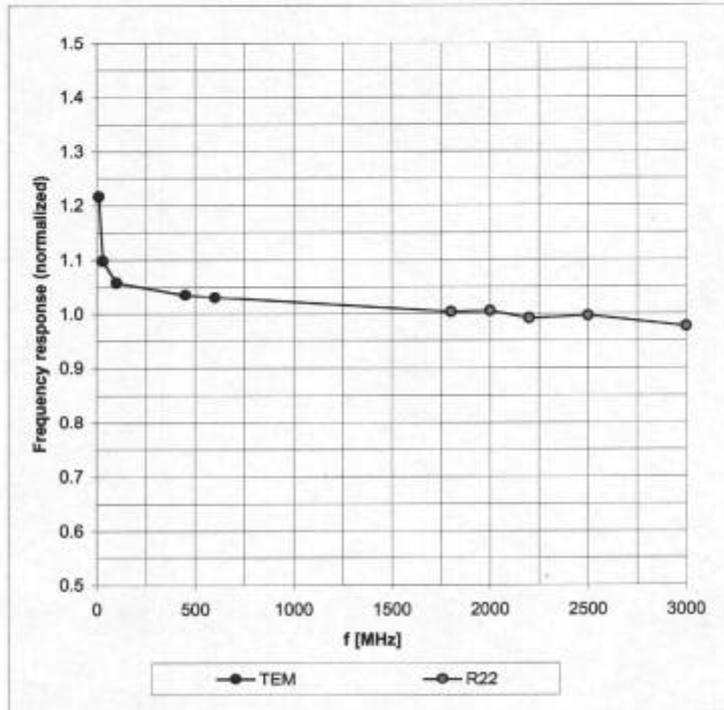


EX3DV4 SN:3660

September 3, 2008

### Frequency Response of E-Field

(TEM-Cell:ifi110 EXX, Waveguide: R22)

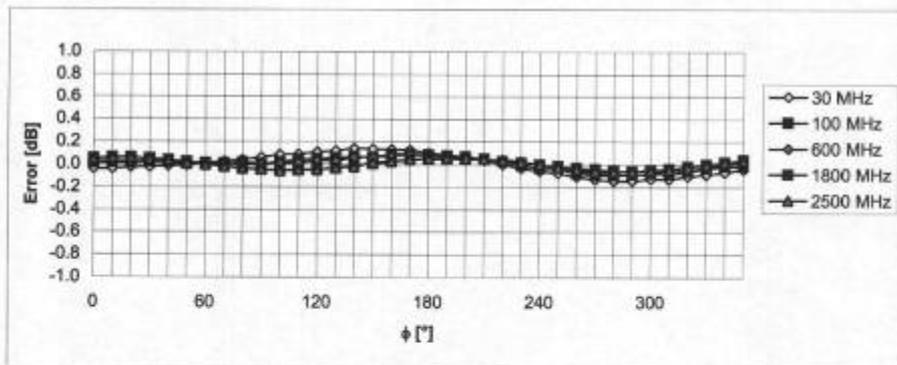
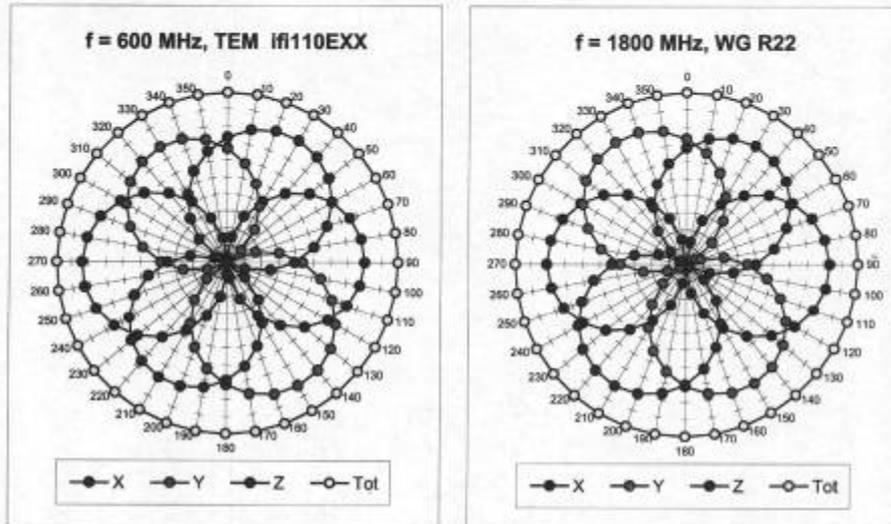


Uncertainty of Frequency Response of E-field:  $\pm 6.3\%$  ( $k=2$ )

EX3DV4 SN:3660

September 3, 2008

Receiving Pattern ( $\phi$ ),  $\vartheta = 0^\circ$

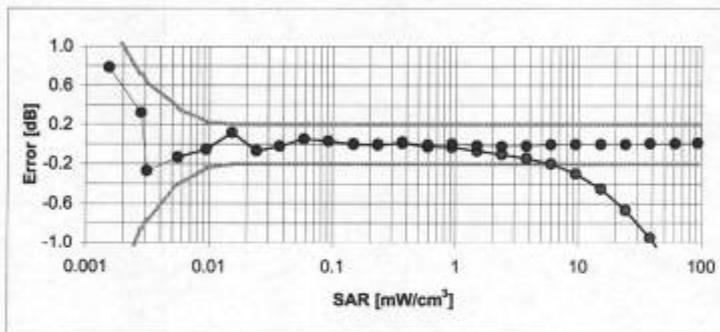
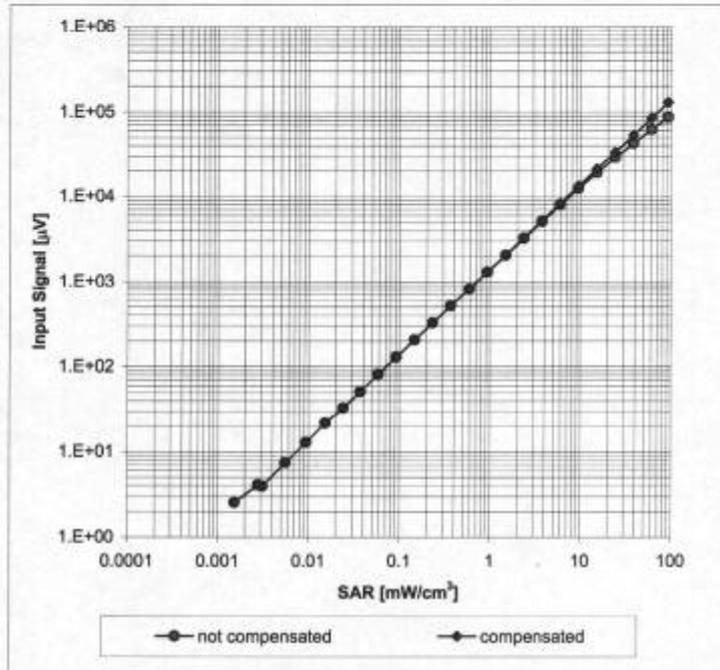


Uncertainty of Axial Isotropy Assessment:  $\pm 0.5\%$  (k=2)

EX3DV4 SN:3660

September 3, 2008

**Dynamic Range  $f(\text{SAR}_{\text{head}})$**   
(Waveguide R22,  $f = 1800$  MHz)

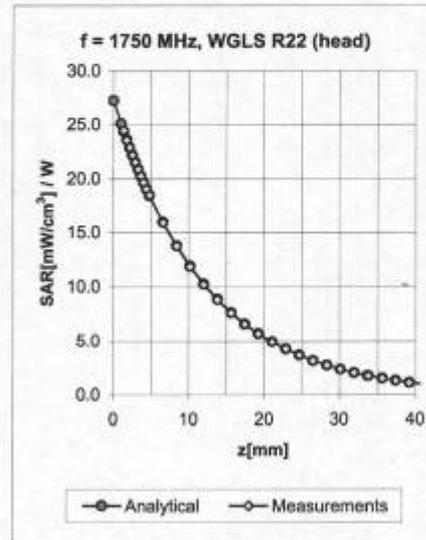
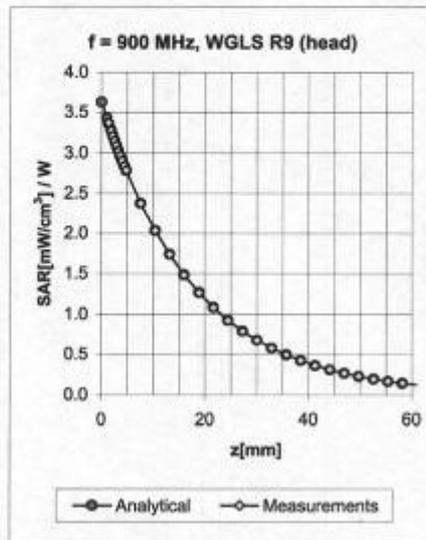


Uncertainty of Linearity Assessment:  $\pm 0.6\%$  ( $k=2$ )

EX3DV4 SN:3660

September 3, 2008

### Conversion Factor Assessment



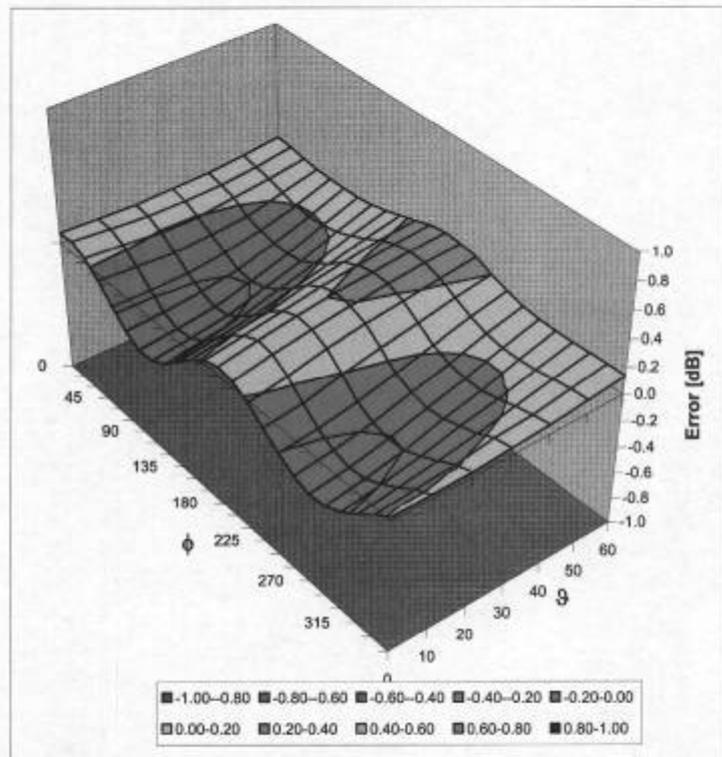
f [MHz]	Validity [MHz] <sup>c</sup>	TSL	Permittivity	Conductivity	Alpha	Depth	ConvF Uncertainty
835	± 50 / ± 100	Head	41.5 ± 5%	0.90 ± 5%	0.49	0.76	9.19 ± 11.0% (k=2)
900	± 50 / ± 100	Head	41.5 ± 5%	0.97 ± 5%	0.43	0.83	8.84 ± 11.0% (k=2)
1750	± 50 / ± 100	Head	40.1 ± 5%	1.37 ± 5%	0.68	0.63	7.79 ± 11.0% (k=2)
1950	± 50 / ± 100	Head	40.0 ± 5%	1.40 ± 5%	0.31	0.80	7.35 ± 11.0% (k=2)
2450	± 50 / ± 100	Head	39.2 ± 5%	1.80 ± 5%	0.32	0.85	6.94 ± 11.0% (k=2)
835	± 50 / ± 100	Body	55.2 ± 5%	0.97 ± 5%	0.63	0.71	9.10 ± 11.0% (k=2)
900	± 50 / ± 100	Body	55.0 ± 5%	1.05 ± 5%	0.30	1.08	8.76 ± 11.0% (k=2)
1750	± 50 / ± 100	Body	53.4 ± 5%	1.49 ± 5%	0.34	0.86	7.55 ± 11.0% (k=2)
1950	± 50 / ± 100	Body	53.3 ± 5%	1.52 ± 5%	0.60	0.67	7.45 ± 11.0% (k=2)
2450	± 50 / ± 100	Body	52.7 ± 5%	1.95 ± 5%	0.30	1.15	6.75 ± 11.0% (k=2)

<sup>c</sup> The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.

EX3DV4 SN:3660

September 3, 2008

**Deviation from Isotropy in HSL**  
Error ( $\phi$ ,  $\theta$ ),  $f = 900$  MHz



Uncertainty of Spherical Isotropy Assessment:  $\pm 2.6\%$  ( $k=2$ )

# TA Technology (Shanghai) Co., Ltd. Test Report

No. RZA2009-0159FCC

Page 87 of 113

## ANNEX E: D835V2 DIPOLE CALIBRATION CERTIFICATE

**Calibration Laboratory of  
Schmid & Partner  
Engineering AG**  
Zeughausstrasse 43, 8004 Zurich, Switzerland



**S** Schweizerischer Kalibrierdienst  
**C** Service suisse d'étalonnage  
**S** Servizio svizzero di taratura  
**S** Swiss Calibration Service

Accredited by the Swiss Accreditation Service (SAS)  
The Swiss Accreditation Service is one of the signatories to the EA  
Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: **SCS 108**

Client **Auden**

Certificate No: **D835V2-4d020\_Jul08**

### CALIBRATION CERTIFICATE

Object **D835V2 - SN: 4d020**

Calibration procedure(s) **QA CAL-05.v7  
Calibration procedure for dipole validation kits**

Calibration date: **July 21, 2008**

Condition of the calibrated item **In Tolerance**

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (Si).  
The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID #	Cal Date (Certificate No.)	Scheduled Calibration
Power meter EPM-442A	GB37480704	04-Oct-07 (No. 217-00736)	Oct-08
Power sensor HP 8481A	US37292783	04-Oct-07 (No. 217-00736)	Oct-08
Reference 20 dB Attenuator	SN: 5086 (20g)	01-Jul-06 (No. 217-00864)	Jul-09
Type-N mismatch combination	SN: 5047.2 / 06327	01-Jul-06 (No. 217-00867)	Jul-09
Reference Probe ES3DV2	SN: 3025	28-Apr-08 (No. ES3-3025_Apr08)	Apr-09
DAE4	SN: 601	14-Mar-08 (No. DAE4-601_Mar08)	Mar-09
Secondary Standards	ID #	Check Date (in house)	Scheduled Check
Power sensor HP 8481A	MY41092317	18-Oct-02 (in house check Oct-07)	In house check: Oct-09
RF generator R&S SMT-06	100005	4-Aug-99 (in house check Oct-07)	In house check: Oct-09
Network Analyzer HP 8753E	US37390585 S4206	18-Oct-01 (in house check Oct-07)	In house check: Oct-08

	Name	Function	Signature
Calibrated by:	Jeton Kastrati	Laboratory Technician	
Approved by:	Katja Pokovic	Technical Manager	

Issued: July 21, 2008

This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

# TA Technology (Shanghai) Co., Ltd.

## Test Report

No. RZA2009-0159FCC

Page 88 of 113

**Calibration Laboratory of  
Schmid & Partner  
Engineering AG**  
Zeughausstrasse 43, 8004 Zurich, Switzerland



**S** Schweizerischer Kalibrierdienst  
**C** Service suisse d'étalonnage  
**S** Servizio svizzero di taratura  
**S** Swiss Calibration Service

Accredited by the Swiss Accreditation Service (SAS)  
The Swiss Accreditation Service is one of the signatories to the EA  
Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: **SCS 108**

### Glossary:

TSL	tissue simulating liquid
ConvF	sensitivity in TSL / NORM $x,y,z$
N/A	not applicable or not measured

### Calibration is Performed According to the Following Standards:

- IEEE Std 1528-2003, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", December 2003
- IEC 62209-1, "Procedure to measure the Specific Absorption Rate (SAR) for hand-held devices used in close proximity to the ear (frequency range of 300 MHz to 3 GHz)", February 2005
- Federal Communications Commission Office of Engineering & Technology (FCC OET), "Evaluating Compliance with FCC Guidelines for Human Exposure to Radiofrequency Electromagnetic Fields; Additional Information for Evaluating Compliance of Mobile and Portable Devices with FCC Limits for Human Exposure to Radiofrequency Emissions", Supplement C (Edition 01-01) to Bulletin 65
- EN 50361, "Basic standard for the measurement of specific absorption rate related to human exposure to electromagnetic fields from mobile phones (300 MHz - 3 GHz)", July 2001

### Additional Documentation:

- DASY4 System Handbook

### Methods Applied and Interpretation of Parameters:

- Measurement Conditions:** Further details are available from the Validation Report at the end of the certificate. All figures stated in the certificate are valid at the frequency indicated.
- Antenna Parameters with TSL:** The dipole is mounted with the spacer to position its feed point exactly below the center marking of the flat phantom section, with the arms oriented parallel to the body axis.
- Feed Point Impedance and Return Loss:** These parameters are measured with the dipole positioned under the liquid filled phantom. The impedance stated is transformed from the measurement at the SMA connector to the feed point. The Return Loss ensures low reflected power. No uncertainty required.
- Electrical Delay:** One-way delay between the SMA connector and the antenna feed point. No uncertainty required.
- SAR measured:** SAR measured at the stated antenna input power.
- SAR normalized:** SAR as measured, normalized to an input power of 1 W at the antenna connector.
- SAR for nominal TSL parameters:** The measured TSL parameters are used to calculate the nominal SAR result.

# TA Technology (Shanghai) Co., Ltd.

## Test Report

### Measurement Conditions

DASY system configuration, as far as not given on page 1.

<b>DASY Version</b>	DASY4	V4.7
<b>Extrapolation</b>	Advanced Extrapolation	
<b>Phantom</b>	Modular Flat Phantom V4.9	
<b>Distance Dipole Center - TSL</b>	15 mm	with Spacer
<b>Zoom Scan Resolution</b>	dx, dy, dz = 5 mm	
<b>Frequency</b>	835 MHz ± 1 MHz	

### Head TSL parameters

The following parameters and calculations were applied.

	Temperature	Permittivity	Conductivity
<b>Nominal Head TSL parameters</b>	22.0 °C	41.5	0.90 mho/m
<b>Measured Head TSL parameters</b>	(22.0 ± 0.2) °C	41.0 ± 6 %	0.89 mho/m ± 6 %
<b>Head TSL temperature during test</b>	(21.6 ± 0.2) °C	---	---

### SAR result with Head TSL

SAR averaged over 1 cm <sup>3</sup> (1 g) of Head TSL	Condition	
SAR measured	250 mW input power	2.30 mW / g
SAR normalized	normalized to 1W	9.20 mW / g
SAR for nominal Head TSL parameters <sup>1</sup>	normalized to 1W	<b>9.20 mW / g ± 17.0 % (k=2)</b>

SAR averaged over 10 cm <sup>3</sup> (10 g) of Head TSL	condition	
SAR measured	250 mW input power	1.52 mW / g
SAR normalized	normalized to 1W	6.08 mW / g
SAR for nominal Head TSL parameters <sup>1</sup>	normalized to 1W	<b>6.07 mW / g ± 16.5 % (k=2)</b>

<sup>1</sup> Correction to nominal TSL parameters according to d), chapter "SAR Sensitivities"

**TA Technology (Shanghai) Co., Ltd.**  
**Test Report**

**Body TSL parameters**

The following parameters and calculations were applied.

	Temperature	Permittivity	Conductivity
<b>Nominal Body TSL parameters</b>	22.0 °C	55.2	0.97 mho/m
<b>Measured Body TSL parameters</b>	(22.0 ± 0.2) °C	53.6 ± 6 %	1.0 mho/m ± 6 %
<b>Body TSL temperature during test</b>	(22.0 ± 0.2) °C	---	---

**SAR result with Body TSL**

<b>SAR averaged over 1 cm<sup>3</sup> (1 g) of Body TSL</b>	Condition	
SAR measured	250 mW input power	2.41 mW / g
SAR normalized	normalized to 1W	9.64 mW / g <sup>2</sup>
SAR for nominal Body TSL parameters <sup>2</sup>	normalized to 1W	<b>9.28 mW / g ± 17.0 % (k=2)</b>

<b>SAR averaged over 10 cm<sup>3</sup> (10 g) of Body TSL</b>	condition	
SAR measured	250 mW input power	1.59 mW / g
SAR normalized	normalized to 1W	6.36 mW / g
SAR for nominal Body TSL parameters <sup>2</sup>	normalized to 1W	<b>6.19 mW / g ± 16.5 % (k=2)</b>

<sup>2</sup> Correction to nominal TSL parameters according to d), chapter "SAR Sensitivities"